**Product Summary** 

900

150

21

26



# 900V GaN Power Transistor (FET)

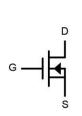
#### **Features**

- Easy to use, compatible with standard gate drivers
- Superior reliability with  $BV_{DSS}$  over 1500V
- Low  $Q_{RR}$ , no free-wheeling diode required
- Excellent Q<sub>G</sub> x R<sub>DS(on)</sub> figure of merit (FOM)
- Low switching loss
- RoHS compliant and Halogen-free

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Αı	gc	lica	atio	ons

- High efficiency power supplies
- Telecom and datacom
- Servo motors
- Automotive



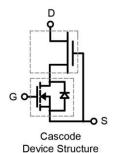


 $V_{DSS}$ 

 $R_{DS(on), \, typ}$ 

 $Q_{G, typ}$ 

 $Q_{RR, \, typ}$ 



 $\boldsymbol{m}\Omega$ 

nC

nC

Schematic Symbol

**Packaging** 

Part Number	Package	Packaging	Base QTY
RX90T150PS2A	3 Lead TO-220	Tube	50

# Maximum ratings, at $T_c$ =25 $^{\circ}$ C, unless otherwise specified

Symbol	Parameter	Limit Value	Unit	
	Continuous drain current @T <sub>C</sub> =25℃	21	Α	
I <sub>D</sub>	Continuous drain current @T <sub>C</sub> =100°C		13	Α
	Pulsed drain current @T <sub>C</sub> =25℃ (pulse	e width: 10us)	80	Α
I <sub>DM</sub>	Pulsed drain current @T <sub>C</sub> =150℃ (pul	se width: 10us)	58	Α
V <sub>DSS</sub>	Drain to source voltage (T₁ = -55℃ to	900	V	
V <sub>TDSS</sub>	Transient drain to source voltage <sup>a</sup>	1000	V	
V <sub>GSS</sub>	Gate to source voltage	±20	V	
P <sub>D</sub>	Maximum power dissipation @T <sub>C</sub> =25℃		100	W
T <sub>C</sub>	O a santia a ta santa	Case	-55 to 150	°C
T <sub>J</sub>	Operating temperature	Junction	-55 to 150	°C
T <sub>S</sub>	Storage temperature		-55 to 150	°C
T <sub>CSOLD</sub>	Soldering peak temperature		260	°C



#### **Thermal Resistance**

Symbol	Parameter	Typical	Unit
Rөлс	Junction-to-case	1.25	℃/W
RөJA	Junction-to-ambient <sup>b</sup>	50	°C/W

#### Notes:

- a. Off-state spike duty cycle < 0.01, spike duration < 2us
- Device on one layer epoxy PCB for drain connection (vertical and without air stream cooling, with 6cm<sup>2</sup> copper area and 70μm thickness)



## Electrical Parameters, at T<sub>J</sub>=25 °C, unless otherwise specified

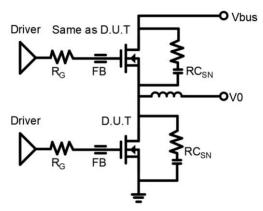
Symbol	Min	Тур	Max	Unit	Test Conditions
Forward Chara	cteristics				
$V_{DSS\text{-MAX}}$	900	-	-	V	V <sub>GS</sub> =0V
$BV_{DSS}$	-	1500	-	V	V <sub>GS</sub> =0V, I <sub>DSS</sub> =250μA
$V_{GS(th)}$	3	4	5	V	$V_{DS}=V_{GS}$ , $I_D=500\mu A$
<b>5</b> C	-	150	190	0	V <sub>GS</sub> =8V, I <sub>D</sub> =4A, T <sub>J</sub> =25℃
$R_{DS(on)}^{c}$	-	300	-	mΩ	V <sub>GS</sub> =8V, I <sub>D</sub> =4A, T <sub>J</sub> =150℃
1	-	5	20	μΑ	V <sub>DS</sub> =900V, V <sub>GS</sub> =0V, T <sub>J</sub> =25℃
I <sub>DSS</sub>	-	50	-	μΑ	$V_{DS}$ =900V, $V_{GS}$ =0V, $T_{J}$ =150 $^{\circ}$ C
1	-	-	150	nA	V <sub>GS</sub> =20V
$I_{GSS}$	-	-	-150	nA	V <sub>GS</sub> =-20V
C <sub>ISS</sub>	-	606	-	pF	
C <sub>OSS</sub>	-	40	-	pF	V <sub>GS</sub> =0V, V <sub>DS</sub> =900V, f=1MHz
$C_{RSS}$	-	3	-	pF	
C <sub>O(er)</sub>	-	57	-	pF	V 9V V 9 999V
C <sub>O(tr)</sub>	-	109	-	pF	V <sub>GS</sub> =0V, V <sub>DS</sub> =0 - 900V
$Q_{G}$	-	21	-		
$Q_{GS}$	-	6.7	-	nC	V <sub>DS</sub> =600V, V <sub>GS</sub> =0 -12V, I <sub>D</sub> =10A
$Q_{GD}$	-	5	-		
t <sub>D(on)</sub>	-	44	-		
t <sub>R</sub>	-	16	-		V 500VV 0 40VV 40A D 40O
t <sub>D(off)</sub>	-	40	-	ns	$V_{DS}$ =600V, $V_{GS}$ =0 - 12V, $I_{D}$ =10A, $R_{G}$ =40 $\Omega$
t <sub>F</sub>	-	12	-		
Reverse Chara	cteristics		1.	1	
	-	1.3	-		V <sub>GS</sub> =0V, I <sub>S</sub> =5A, T <sub>J</sub> =25℃
$V_{SD}$	-	1.9	-	V	V <sub>GS</sub> =0V, I <sub>S</sub> =10A, T <sub>J</sub> =25℃
	-	3	-		V <sub>GS</sub> =0V, I <sub>S</sub> =10A, T <sub>J</sub> =150℃
t <sub>RR</sub>	-	16	-	ns	
$Q_{RR}$	-	26	-	nC	$I_S$ =10A, $V_{GS}$ =0V, $d_i/d_t$ =1000A/us, $V_{DD}$ =600V

#### Notes:

c. Dynamic on-resistance; see Figure 17 and 18 for test circuit and configurations



## **Circuit Implementation**



# **Recommended Single Ended Drive Circuit**

Recommended gate drive: (0 V, 12 V) with  $R_{G(tot)}$  = 41  $\Omega$ , where  $R_{G(tot)}$  =  $R_G$  +  $R_{Driver}$ 

Gate Ferrite Bead	Gate Resistance1	RC Snubber
(FB)	(R <sub>G</sub> )	(RC <sub>SN</sub> )
MPZ1608S471ATA00	40 Ω	69 pF+ 15 Ω

#### Notes:

- d. RCsn should be placed as close as possible to the drain pin
- e. The layout and wiring of the drive circuit should be as short as possible



#### Typical Characteristics, at T<sub>C</sub>=25 ℃, unless otherwise specified

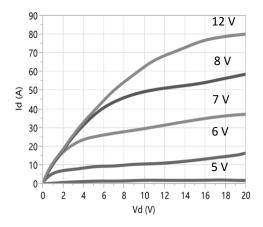


Figure 1. Typical Output Characteristics T₁=25℃

Parameter: V<sub>GS</sub>

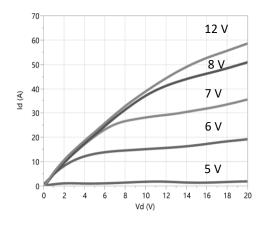
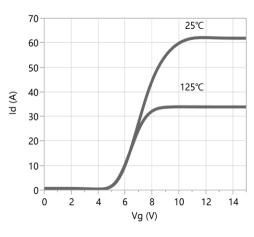


Figure 2. Typical Output Characteristics T<sub>J</sub>=150℃

Parameter: V<sub>GS</sub>



**Figure 3. Typical Transfer Characteristics** 

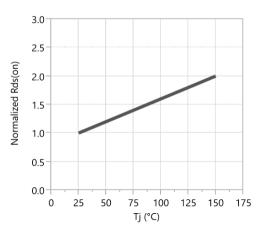


Figure 4. Normalized On-resistance

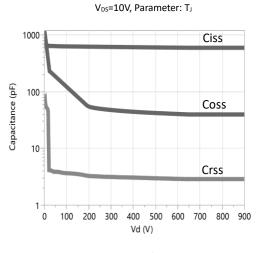


Figure 5. Typical Capacitance

V<sub>GS</sub>=0V, f=1MHZ

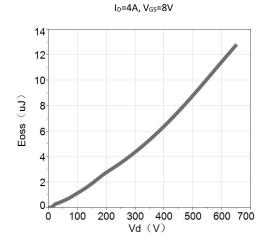


Figure 6. Typical Coss Stored Energy



#### Typical Characteristics, at T<sub>C</sub>=25 ℃, unless otherwise specified

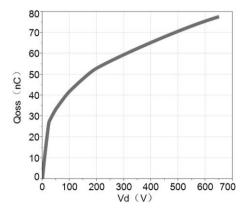
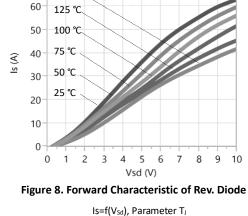


Figure 7. Typical Qoss



150 ℃

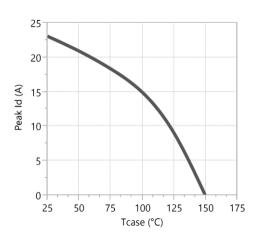


Figure 9. Current Derating

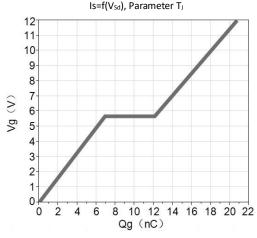


Figure 10. Typical Gate Charge

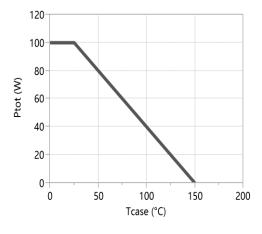


Figure 11. Power Dissipation

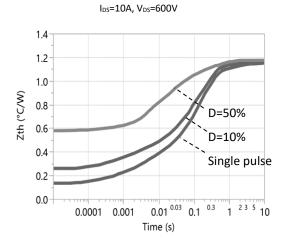


Figure 12. Transient Thermal Resistance





# Typical Characteristics, at T<sub>C</sub>=25 ℃, unless otherwise specified

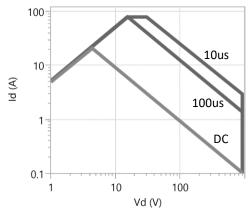


Figure 13. Safe operating Area  $T_c$ =25  $^{\circ}$ C

(calculated based on thermal limit)

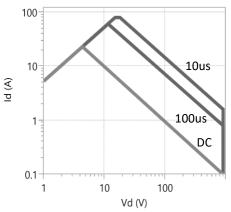


Figure 14. Safe operating Area T<sub>C</sub>=80 ℃

(calculated based on thermal limit)



#### **Test Circuits and Waveforms**

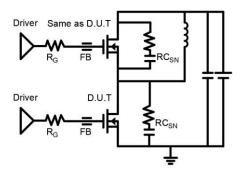


Figure 15. Switching Time Test Circuit

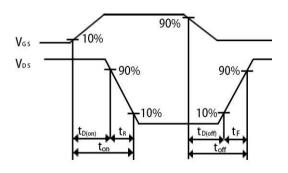


Figure 16. Switching Time Waveform

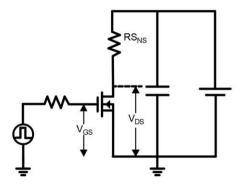


Figure 17. Dynamic  $R_{DS(on)}$  Test Circuit

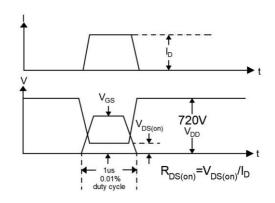


Figure 18. Dynamic  $R_{DS(on)}$  Waveform

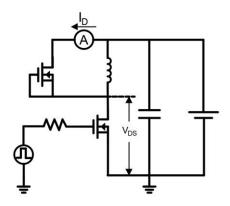


Figure 19. Diode Characteristic Test Circuit

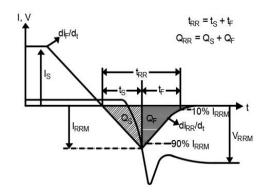


Figure 20. Diode Recovery Waveform



#### **Design Considerations**

Fast switching GaN device can reduce power conversion losses, and thus enable high frequency operations. Certain PCB design rules and instructions, however, need to be followed to take full advantages of fast switching GaN devices.

Before evaluating Runxin Micro's GaN devices, please refer to the table below which provides some practical rules that should be followed during the evaluation.

#### When Evaluating Runxin Micro's GaN Devices:

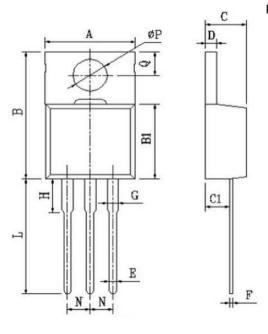
DO	DO NOT
Make sure the traces are as short as possible for both	Using Runxin Micro's devices in GDS board layouts
drive and power loops to minimize parasitic inductance	
Use the test tool with the shortest inductive loop, and	Use differential mode probe or probe ground clip with
make sure test points should be placed close enough	long wires
Minimize the lead length of TO packages when	Use long traces in drive circuit, or long lead length of
installing them to PCB	the devices



# **Package Outline**

#### 3 Lead TO-220 (PS) Package

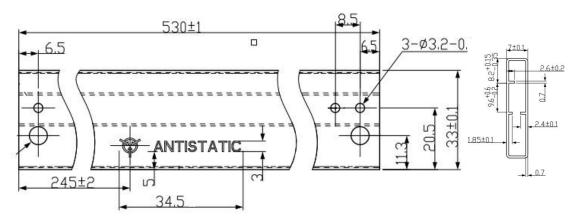
Pin 1: Gate; Pin 2: Source; Pin 3: Drain; Tab: Source



COMM	ON DIMEN	SIONS
SYMBOL	Ŋ	M
SIMDUL	MIN	MAX
A	10.1	10.5
В	15.2	15.6
B1	9.00	9.40
C	4.40	4.60
C1	2.40	3.00
D	1.20	1.40
Е	0.70	0.90
F	0.30	0.50
G	1.17	1.37
Н	3.30	3.80
L	13. 1	13.7
N	2.34	2.74
Q	2.40	3.00
ФР	3.70	3.90

#### **Tube Information**

#### Dimensions are shown in millimeters



## **Revision History**

Version	Date	Change(s)
1.0	06/22/2022	Release formal datasheet
1.1	10/27/2022	Revise $C_{O(er)}$ , $C_{O(tr)}$ , $Q_G$ , $Q_{GS}$ , $Q_{GD}$
1.2	02/16/2023	Revise BV <sub>DSS</sub> ,Revise I <sub>D</sub>
1.3	03/10/2023	Revise Package Outline